

INVITATION TO THE PRESENTATION ABOUT THE WORKPLACEMENT

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**“Evaluation of X-ray micrographs of power
semiconductors”**



<https://classroom.aau.at/b70pi> Friday, 29 May 2020
rjr-3wy

🕒 2:00 p.m.

Abstract

The internship semester took place in the department of failure analysis at Infineon Technologies Austria AG. In the laboratory analyses of failed semiconductor devices are performed. One of these analysis methods is the X-ray. The main topic of this internship semester was the evaluation of X-ray-micrographs with the aid of the image processing program “ImageJ”.

Jürgen Pilz and the Department of Statistics look forward to seeing you at the talk!